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TSMC-01-1357D

May 11, 2004

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject:

Serial No. 10/821,270 04/08/04

Yi-Hsu Wu et al.

WHOLE CHIP ESD PROTECTION

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450, on May 17, 2004.

Stephen B. Ackerman, Reg. # 37761

Signature/Date

Stephen B. Ackerman 5/17/04

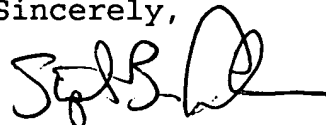
TSMC-01-1357D

U.S. Patent 6,344,412 to Ichikawa et al., "Integrated ESD Protection Method and System," describes a method and a system for protecting integrated circuits from electrostatic discharge damage.

U.S. Patent 6,262,873 to Pequignot et al., "Method for Providing ESD Protection for an Integrated Circuit," discloses a method for providing electrostatic protection for integrated circuits.

U.S. Patent 6,218,704 to Brown et al., "ESD Protection Structure and Method," discloses an integrated circuit structure and method for electrostatic discharge protection for chips.

Sincerely,

A handwritten signature in black ink, appearing to read 'SBA', with a large, stylized loop at the end.

Stephen B. Ackerman,
Reg. No. 37761

MAY 19 2004 IN AN APPLICATION

(Use several sheets if necessary)

Doche (Humboldt) (Cyprian)

Agitation Number

TSMC-01-13570 | 0 | 821, 270

Applicant Yi-Hsun Wu et al.

Filing Date

04/08/04

Group Art Unit

U. S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Portion or Pages, Etc.)

EXAMINE

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.